Atty. Dkt. No: SYN-0174

AF ZKW
2133

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Thomas W. Williams et al.
Application No.: 09/728,022 Art Unit.: 2133
Filing Date: 11/30/2000 Examiner: John J. Tabone, Jr.
For: "Intelligent Test ector Formatting To Reduce Test Vector Size And Allow Encryption Thereof For Integrated Circuit Testing"

Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Date: October 11, 2005

AMENDMENT TRANSMITTAL

1. Transmitted herewith is an amendment for this application.

2. **STATUS**: Applicant is other than a small entity.

3. **EXTENSION OF TERM:** The proceedings herein are for a patent application and the provisions of 37 C.F.R. 1.136 apply. Applicant believes that no extension of term is required. However, this conditional petition is being made to provide for the possibility that applicant has inadvertently overlooked the need for a petition for extension of time.

4. **FEE FOR CLAIMS:** The fee for claims (37 C.F.R. 1.16(b)-(d)) has been calculated as shown below:

	(Col.1) Claims Remaining After Amendment		(Col. 2) Highest No. Previously Paid For	(Col. 3) Present Extra	LARGE ENTITY Rate	Addit. Fee
Total	11	Minus	20	= 0	x $50 =	$0
Indep.	2	Minus	3	= 0	x $200 =	$0
First Presentation of Multiple Dependent Claim					+ $360 =	$0
					Total Addit. Fee	$0

No additional fee for claims is required.

5. **FEE DEFICIENCY:** If any additional extension and/or fee is required, please charge Deposit Account No. 50-0574.

SIGNATURE OF PRACTITIONER
Jeanette S. Harms
Reg. No. 35,537

Customer No. 35273
Tel.: (408) 451-5907

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as FIRST CLASS MAIL in an envelope addressed to: Mail Stop AF, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on October 11, 2005.

10/11/2005
Date

Signature: Rebecca A Baumann

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Thomas W. Williams et al.

Assignee: Synopsys, Inc.

Title: INTELLIGENT TEST VECTOR FORMATTING TO REDUCE TEST VECTOR SIZE AND ALLOW ENCRYPTION THEREOF FOR INTEGRATED CIRCUIT TESTING

Serial No.: 09/728,022 File Date: November 30, 2000

Examiner: John J. Tabone Jr. Art Unit: 2133

Docket No.: SYN-0174

Date: October 11, 2005

Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT IN RESPONSE TO THE FINAL OFFICE ACTION

Initial Comments

Claims 7-13 and 17-20 are pending in this application.

Claims 7-10, 13, 17, 19, and 20 are rejected under 35 U.S.C. 103(a) as being unpatentable over U.S. Patent 5,444,716 (Jarwala). Claims 11, 12, and 18 are rejected under 35 U.S.C. 103(a) as being unpatentable over Jarwala in view of U.S. Patent 6,101,622 (Lesmeister).

No claims are amended herein.